

<b>Notice of References Cited</b>	Application/Control No. 10/811,621	Applicant(s)/Patent Under Reexamination SHIH ET AL.	
	Examiner Edna Wong	Art Unit 1795	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,638,621	10-2003	Anderson, David	428/402.24
*	C	US-6,689,223	02-2004	Meine et al.	134/2
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	BASF, "Surfactants: Pluronic & Tetronic" (no date), pp. 1-40.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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